		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 17116/003003		SERIAL NO. 10/714,454	
<b>INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)				APPLICANT    Wakil et al.			
				FILING DATE: November 14, 2003		GROUP: 3737	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	Subclass	FILING DATE IF APPROPRIATE	
JRS	AA 3 2 9 0 9 2 7	12/13/66	Gambs	73	80	07/06/59	
	AB 4 6 9 1 7 1 6	09/08/87	Tanne	128	774	05/27/86	
	AC 4 7 9 6 9 8 9	01/10/89	Fukuma et al.	351	212	07/15/87	
	AD 5 1 4 8 2 0 5	09/15/92	Guilino et al.	351	159	06/22/89	
	AE 5 2 5 8 7 9 1	11/02/93	Penney et al.	351	211	07/24/90	
	AF 5 2 9 3 8 7 1	03/15/94	Reinstein et al.	128	660.06	07/09/93	
	AG 5 4 1 4 4 7 8	05/09/95	van Gelderen	351	212	09/22/93	
	AH 5 4 1 8 7 1 4	05/23/95	Sarver	364	413.13	04/08/93	
	AI 5 5 8 1 4 0 5	12/03/96	Meyers et al.	359	571	08/17/94	
	AJ 5 5 8 9 8 9 7	12/31/96	Sinclair et al.	351	223	12/22/95	
	AK 5 7 2 2 4 2 7	03/03/98	Wakil et al.	128	898	12/13/94	
	AL 5 8 4 1 5 1 1	11/24/98	D'Souza et al.	351	212	10/23/96	
	AM 5 8 4 7 8 0 4	12/08/98	Sarver et al.	351	206	04/25/96	
	AN 5 8 7 5 0 1 9	02/23/99	Villani	351	211	11/21/95	
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.).							
	AO	Corneal Topography The State of the Art by James P. Gills, Donald R. Sanders, Spencer P. Thornton, Robert G. Martin, Johnny L. Gayton, Jack T. Holladay - Chapter 5 - The EyeSys 2000 Corneal Analysis System by Spencer P. Thornton, M.D. FACS and Joseph Wakil, M.D. MEE					
	AP	EyeSys 2000 Corneal Analysis System: The Ultimate in Corneal Topography from the Proven Leader (Brochure). Copyright EyeSys Technologies, Inc., 1995					
V	AQ	EyeSys Vista: Hand-Held Corneal Topographer (Brochure)					
	AR	Ophthalmic Terminology: Speller and Vocabulary Builder - Third Edition - by Stein, Slatt, and Stein					
EXAMINER DATE CONSIDERED    /John R Sanders Jr/    09/21/2006							
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	APPLICANT    Wakil et al.			
	FILING DATE: November 14, 2003		GROUP: 3737	

U.S. PATENT DOCUMENTS

EXAMINER'S INITIAL		DOCUMENT NUMBER								DATE	NAME	CLASS	Subclass	FILING DATE IF APPROPRIATE
JRS	BA	5	9	5	3	1	0	0		09/14/99	Sarver et al.	351	206	10/23/97
	BB	6	0	0	0	8	0	0		12/14/99	Webb et al.	351	211	06/22/98
	BC	6	0	8	2	8	5	6		07/04/00	Dunn et al.	351	160	11/09/98
	BD	6	2	3	4	6	3	1		05/22/01	Sarver et al.	351	212	03/09/00
	BE	6	4	0	9	3	4	5		06/25/02	Molebny et al.	351	212	08/08/00
	BF	4	1	9	0	3	3	2		02/26/80	Body et al.	351	211	10/14/77
	BG	4	7	7	8	2	6	8		10/18/88	Randle	351	203	02/06/86
	BH	6	3	8	2	7	9	7		05/07/02	Bille et al.	351	212	10/17/00
	BI	6	3	8	2	7	9	5		05/07/02	Lai	351	212	5/20/00
	BJ	6	1	9	9	9	8	6		03/13/01	Williams et al.	351	221	10/21/99
	BK	6	0	0	4	3	1	3		12/21/99	Shimmick et al.	606	5	6/26/98
	BL	4	4	6	5	3	4	8		08/14/84	Lang et al.	351	211	11/24/81

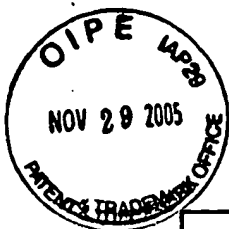
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.).

	BM	Contact Lenses: Update 1 - Chapter 4 - Corneal Topgraphy by J. James Rowsey and David J. Schanzlin (Copyright 1986 by Little, Brouwn and Company)
	BN	Contact Lenses - Chapter 17 - Measurement of Corneal Curvature: Keratometer (Ophthalmometer) by Oliver H. Dabezies, Jr. and Jack T. Holladay (Copyright 1984 by Little, Brown and Company)
	BO	A Comprehensive Guide to Fitting Contact Lenses with EyeSys Pro-Fit Contact Lens Fitting Software by Beth A. Soper, C.O.A. (EyeSys System 2000 - Version 3.1)
↓	BP	M.S. Smirnov. Measurement and wave aberration of the eye. Biofizika (Biophysics USSR), 6, pp 687 through 703 (previously pp. 776-794, 1961). English translation of: p. 690 translation of the last paragraph continuing onto p. 691, and on page 691 1 <sup>st</sup> , 2 <sup>nd</sup> and 3 <sup>rd</sup> full paragraphs.

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In Place of Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 17116/003003		SERIAL NO. 10/714,454							
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Wakil et al.									
				FILING DATE: November 14, 2003		GROUP: 3737							
FOREIGN PATENT DOCUMENTS													
EXAMINER'S INITIAL			DOCUMENT NUMBER						DATE	COUNTRY	TRANSLATION		
JRS	CA		6	3	2	4	2	2	1	9	10/07/88	JAPAN	in English
	CB		9	8	1	0	5	2	8	6	07/10/98 (Filing Date)	UKRAINE	in English
	CC	PCT/US99/	2	3	3	2	7				07/10/99 (Filing Date)	PCT	in English
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.).													
	CD	Van de Brink. Measurement of the geometrical aberrations of the eye. Vision Res. 2, pp. 233-244, 1962											
	CE	N.M. Sergienko. Oftalmologicheskaya optika (Ophtalmic Optics). Moscow, Meditsina, 1991, 142 pages. English translation of: p. 30-32 text of the last paragraph referring to Figure 19 continuing onto pages 31 and 32, and first full paragraph of page 32.											
	CF	R.H. Webb, C.M. Penney, and K.D. Thompson. Measurement of ocular local wavefront distortion with a spatially resolved refractometer. Applied Optics. 31, pp. 3678-3686, 1992.											
	CG	S.G. El Hage and Berni F. Contribution of the crystalline lens to the spherical aberration of the eye. J. Opt. Soc. Am. 63, pp. 205-211, 1973											
	CH	J. Liang, B. Grimm, S. Goelz, and J. F. Bille, Objective measurement of wave aberrations of the human eye with the use of a Hartmann-Shack wave-front sensor. J Opt. Soc. A. 11, pp. 1949-1957, 1994.											
	CI	J. Liang and D.R. Williams. Aberrations and retinal image quality of the normal human eye. J Opt. Soc. Am. A 14, pp. 2873-2883, 1997.											
	CJ	J. Liang, D.R. Williams and D.T. Miller. Supernormal vision and high resolution retinal imaging through adaptive optics, J. Opt. Soc. Am., A 14, pp. 2884-2892, 1997.											
	CK	T. Seiler, P.J. McDonnell, "Excimer laser photorefractive keratectomy", Surv. of Ophthalm., 40, pp. 89-118, 1995.											
	CL	United States Patent application no. 10/137,720. Molebny et al. filed 05/01/2002. Publication no. 2003/0011745. Published 01/16/2003.											
	CM	Eye Sys Technologies brochure. EyeSys Software The power that drives high performance corneal topography. EyeSys Technologies Inc., 1995.											
✓	CN	W.D. West, OD. Corneal Topography: It's not just for surgeons anymore. Eyecare Technology, July/August, 1995											
	CO												
EXAMINER DATE CONSIDERED /John R Sanders Jr/ 09/21/2006													
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PTO/SB/08a/b (07-05)

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<b>Substitute for form 1449A/B/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/714,454-Conf. #9376
				Filing Date	November 14, 2003
				First Named Inventor	Youssef S. Wakil
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	17116/003003

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
JRS	AA*	US-6,305,802-B1	10-23-2001	Roffman et al.	
JRS	AB*	US-2003/0199858-A1	10-23-2003	Schelonka	
JRS	AC*	US-2003/0142271-A1	07-31-2003	Ross et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials *	Cite No.¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T³
		Country Code²-Number⁴-Kind Code⁵ (if known)	MM-DD-YYYY			

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>

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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	/John R Sanders Jr/	Date Considered	09/21/2006
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